

1.0 SCOPE

This specification covers the detail requirements for a precision voltage reference which provides a stable +10V output that can be adjusted over a $\pm 3\%$ range with minimal effect on temperature stability. Long term stability of the REF-10 is qualified by sample wafer lot testing to a limit of 50ppm/1000 hours maximum.

It is highly recommended that this data sheet be used as a baseline for new military or aerospace spec control drawings.

1.2 Part Number. The complete part numbers per Table I of this specification follow:

<u>Device</u>	<u>Part Number</u>	<u>Package</u>
A	REF-10AJ/883	J
B	REF-10BJ/883	J

1.2.3 Case Outline.

<u>Letter</u>	<u>Case Outline (Lead finish per MIL-M-38510)</u>
J	8-lead metal can (TO-99)

1.3 Absolute Maximum Ratings. ($T_A = 25^\circ C$, unless otherwise noted)

Input Voltage	40V
Power Dissipation	500mW
Output Short-Circuit Duration (to Ground or V_{IN})	Indefinite
Storage Temperature Range	-65°C to +150°C
Operating Temperature Range	-55°C to +125°C
Lead Temperature (Soldering, 60 sec)	+300°C
DICE Junction Temperature Range (T_J)	-65°C to +150°C

1.5 Thermal Characteristics:

Thermal Resistance, TO-99 (J) package:

Junction-to-Case (Θ_{JC}) = $45^\circ C/W$ MAX

Junction-to-Ambient (Θ_{JA}) = $150^\circ C/W$ MAX

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TABLE 1

$V_{IN} = 15V$; $T_A = 25^\circ C$ unless otherwise specified.

Characteristics	Symbol	Special Conditions	REF-10/883				Units
			Min	Max	Min	Max	
Quiescent Supply Current	I_{SY}	No Load $-55^\circ C \leq T_A \leq +125^\circ C$	—	1.4	—	1.4	mA
Output Voltage	V_O	$I_L = 0$ $-55^\circ C \leq T_A \leq +125^\circ C$	9.970 9.955	10.030 10.045	9.950 9.905	10.050 10.095	V
Output Voltage Temperature Coefficient (Notes 1, 4)	TCV_O	$-55^\circ C \leq T_A \leq +125^\circ C$	—	8.5	—	25 ppm/ $^\circ C$	
Short-Circuit Current	I_{SC}	$V_O = 0$	+15	+60	+15	+60	mA
Sink Current	I_S		-0.3	—	-0.3	—	mA
Load Regulation (Note 2)	LD_{reg}	$I_L = 0mA$ to $10mA$ $I_L = 0mA$ to $8mA$ $-55^\circ C \leq T_A \leq +125^\circ C$	— —	0.008 0.012	— —	0.010 0.015	%/mA
Line Regulation (Note 2)	LN_{reg}	$V_{IN} = 13V$ to $33V$ $-55^\circ C \leq T_A \leq +125^\circ C$	— —	0.010 0.015	— —	0.010 0.015	%/V
Load Current (Note 3)	I_L		10	—	10	—	mA
Output Adjustment Range	ΔV_{trim}	$R_p = 10k\Omega$	±3.0	—	±3.0	—	%
Output Voltage Noise (Note 4)	e_{np-p}	0.1Hz to 10Hz	—	30	—	30	μV_{p-p}
Long-Term Stability (Note 5)			—	50	—	50	ppm/ 1kHrs

NOTES:

$$1. TCV_O = ABS \left(\frac{V_{MAX} - V_{MIN}}{10V} \right) \left(\frac{1}{180^\circ C} \right) \left(10^6 \right) \text{ where } -55^\circ C \leq T_A \leq +125^\circ C.$$

2. Line and Load Regulation specifications include the effect of self-heating.

3. Minimum of 10mA Load Current guaranteed by Load Regulation test.

4. This parameter is 100% tested.

5. Each wafer lot is tested for Long-Term Stability at a chip temperature of $76^\circ C$ for 168 hours. The sample size is 105 units with an LTPD of 5/2.

TABLE 2

REF-10/883

**Electrical Test Requirements
For Class B Devices**

MIL-STD-883 Test Requirements	Subgroups (see Table 3)
Interim Electrical Parameters (pre Burn-In)	1
Final Electrical Test Parameters	1*, 2, 3, 8
Group A Test Requirements	1, 2, 3, 8

* PDA applies to Subgroup 1 only.
No other Subgroups are included in PDA.

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TABLE 3

Group A Inspection

$V_{IN} = 15V; T_A = T_J$ unless otherwise specified.

Test Requirement	Symbol	Special Conditions	REF-10/883				Units
			Min	Max	Min	Max	
Subgroup 1 $T_A = +25^\circ C$	I_{SY}	No Load	—	1.4	—	1.4	mA
	ΔV_{trim}	$R_p = 10k\Omega$	± 3.0	—	± 3.0	—	%
	V_O	$I_L = 0$	9.970	10.030	9.950	10.050	V
	I_{SC}	$V_O = 0$	+15	+60	+15	+60	mA
	I_S		-0.3	—	-0.3	—	mA
	LD_{reg}	$I_L = 0mA, 10mA$ (Note 2)	--	0.008	—	0.010	%/mA
	LN_{reg}	$V_{IN} = 13V, 33V$ (Note 2)	--	0.010	—	0.010	%/V
Subgroup 2 $T_A = +125^\circ C$	I_{SY}	No Load	—	2.0	—	2.0	mA
	V_O		9.955	10.045	9.905	10.095	V
	LD_{reg}	$I_L = 0mA, 8mA$ (Note 2)	--	0.012	—	0.015	%/mA
	LN_{reg}	$V_{IN} = 13V, 33V$ (Note 2)	--	0.015	—	0.015	%/V
Subgroup 3 $T_A = -55^\circ C$	I_{SY}	No Load	—	2.0	—	2.0	mA
	V_O		9.955	10.045	9.905	10.095	V
	LD_{reg}	$I_L = 0mA, 8mA$ (Note 2)	--	0.012	—	0.015	%/mA
	LN_{reg}	$V_{IN} = 13V, 33V$ (Note 2)	--	0.015	—	0.015	%/V
Subgroup 8 $-55^\circ C \leq T_A \leq +125^\circ C$	TCV_O	(Notes 1, 4)	—	8.5	—	25	ppm/ $^\circ C$

NOTES:

1. $TCV_O = ABS \left(\frac{V_{MAX} - V_{MIN}}{10V} \right) \left(\frac{1}{180^\circ C} \right) \left(10^6 \right)$ where $-55^\circ C \leq T_A \leq +125^\circ C$.
2. Line and Load Regulation specifications include the effect of self-heating.
3. Minimum of 10mA Load Current guaranteed by Load Regulation test.
4. This parameter is 100% tested.